

SIGC223T120R2CL

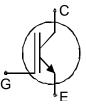
IGBT Chip in NPT-technology

FEATURES:

- 1200V NPT technology
- 180µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling

This chip is used for:

- IGBT-Modules
 BSM150GB120DLC
- Applications:
- drives



Chip Type	V _{CE}	I Cn	Die Size	Package	Ordering Code
SIGC223T120R2CL	1200V	150A	14.4 x 15.5 mm ²	sawn on foil	Q67050-A4286- A101

MECHANICAL PARAMETER:

Raster size	14.4 x 15.5 ^m				
Area total / active	223.2 / 189.9				
Emitter pad size	8x(3.67x6.77)				
Gate pad size	1.49 x 1.51				
Thickness	180	μm			
Wafer size	150	mm			
Flat position	90	deg			
Max.possible chips per wafer	54 pcs				
Passivation frontside	Photoimide				
Emitter metalization	3200 nm Al Si 1%				
Collector metalization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	AI, ≤500µm				
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm				
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



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MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit	
Collector-emitter voltage, Tj=25 °C	V _{CE}	1200	V	
DC collector current, limited by T _{jmax}	I _C	1)	А	
Pulsed collector current, t_p limited by T_{jmax}	I _{cpuls}	450	Α	
Gate emitter voltage	V _{GE}	±20	V	
Operating junction and storage temperature	T _j , T _{stg}	-55 +150	°C	

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
i arameter		Conditions	min.	typ.	max.	onne
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V , I _C =8 mA	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =150A	1.8	2.2	2.6	V
Gate-emitter threshold voltage	V _{GE(th)}	I_C =6mA , V_{GE} = V_{CE}	4.5	5.5	6.5	
Zero gate voltage collector current	I _{CES}	V_{CE} =1200V , V_{GE} =0V			18.2	μA
Gate-emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =20V			600	nA

DYNAMIC CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
Falameter			min.	typ.	max.	
Input capacitance	Ciss	V _{CE} =25V,	-	11	-	nF
Output capacitance	Coss	$V_{GE}=0V$,	-	-	-	
Reverse transfer capacitance	Crss	f=1MHz	-	0.7	-	

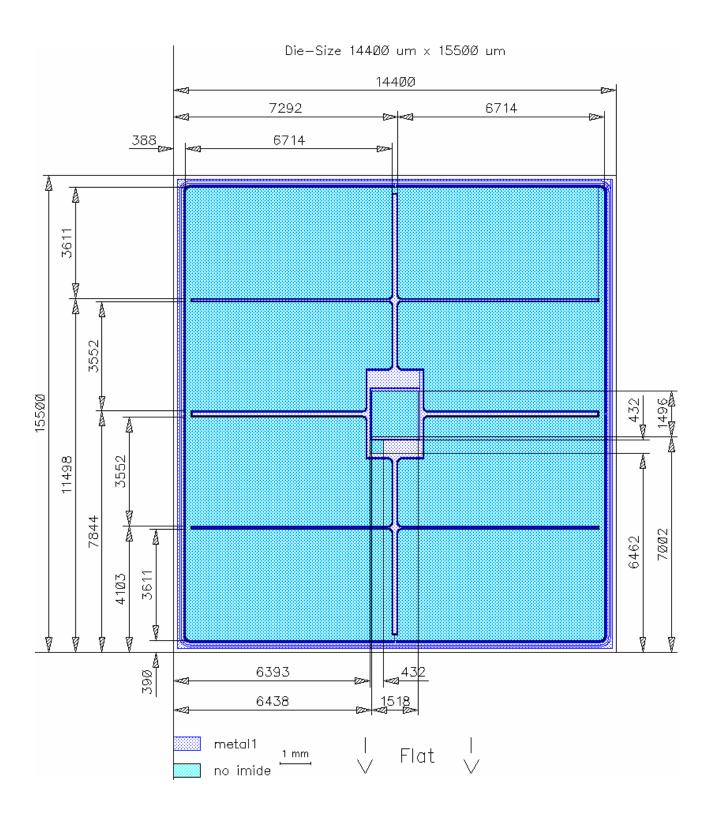
SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

Parameter	Symbol	Conditions ¹⁾	Value			Unit
	Symbol		min.	typ.	max.	Unit
Turn-on delay time	t _{d(on)}	$T_{\rm j} = 125^{\circ} \rm C$	-	50	-	ns
Rise time	t _r	· V _{CC} =600V, I _C =150A	-	50	-	
Turn-off delay time	t _{d(off)}	$V_{\rm GE}=\pm 15 V,$ $R_{\rm G}=5.6 \Omega$	-	570	-	
Fall time	t _f	NG-0.022	-	40	-	

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





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FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

BSM150GB120DLC

Half-Bridge 62mm

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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